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United States Patent [19]

Yamakoshi et al.

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[54] **ANALOG MULTI-METER**

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[**] Term: **14 Years**

[21] Appl. No.: **67,663**

[22] Filed: **Mar. 6, 1997**

[30] **Foreign Application Priority Data**

Jan. 20, 1997 [JP] Japan 9-1124

[51] **LOC (6) Cl.** **10-04**
[52] **U.S. Cl.** **D10/78**
[58] **Field of Search** D10/78; 324/110, 324/115; 340/635, 686, 687, 693

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 300,306 3/1989 Arnoux et al. D10/78
D. 366,432 1/1996 Wrisley et al. D10/78

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Attorney, Agent, or Firm—Kanesaka & Takeuchi

[57] **CLAIM**

The ornamental design for an analog multi-meter, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of an analog multi-meter, with the scale omitted, showing our new design;

FIG. **2** is a front view thereof;

FIG. **3** is a right side view thereof;

FIG. **4** is a left side view thereof;

FIG. **5** is a rear view thereof;

FIG. **6** is a top plan view thereof; and,

FIG. **7** is a bottom view thereof.

1 Claim, 4 Drawing Sheets

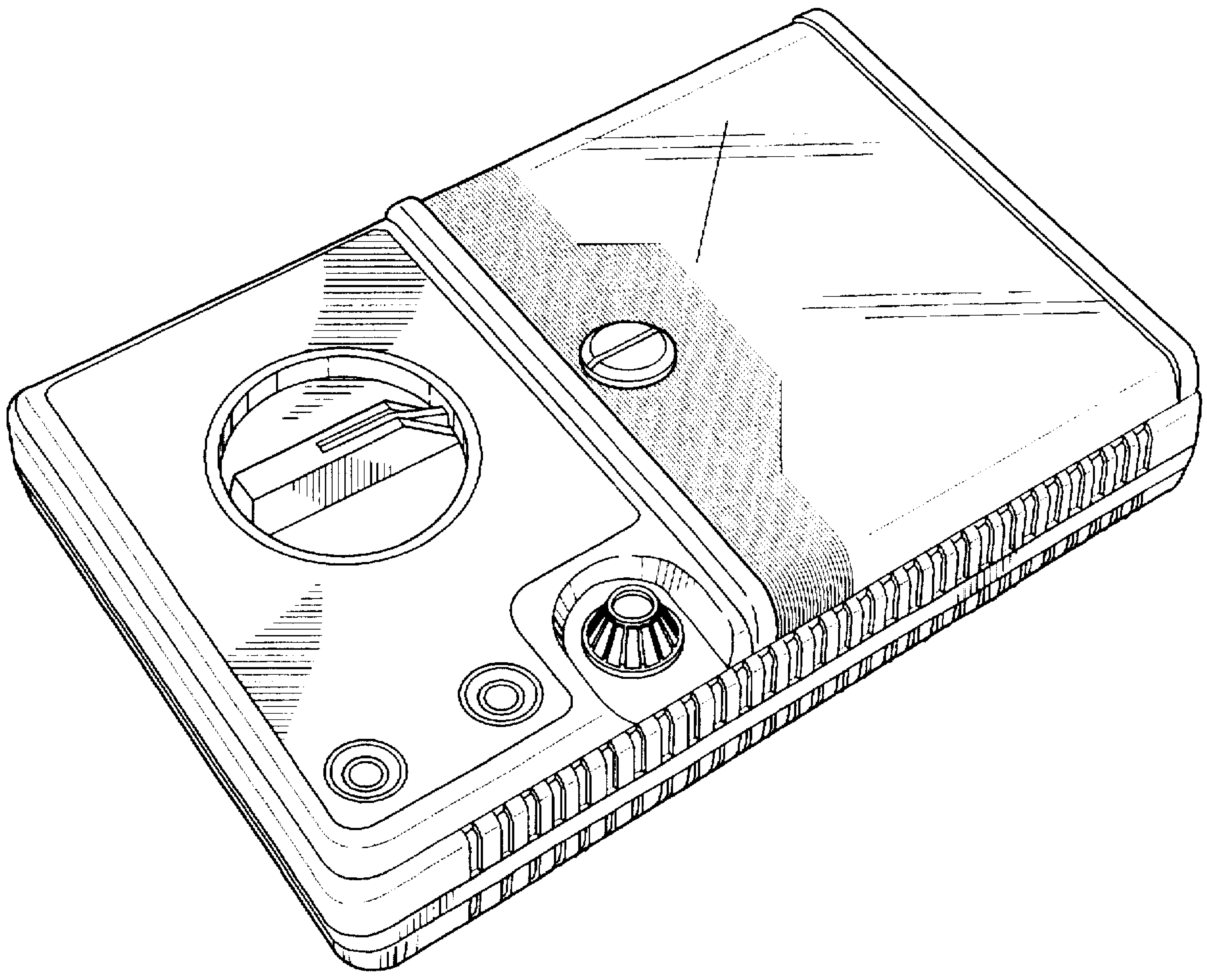

FIG. 1

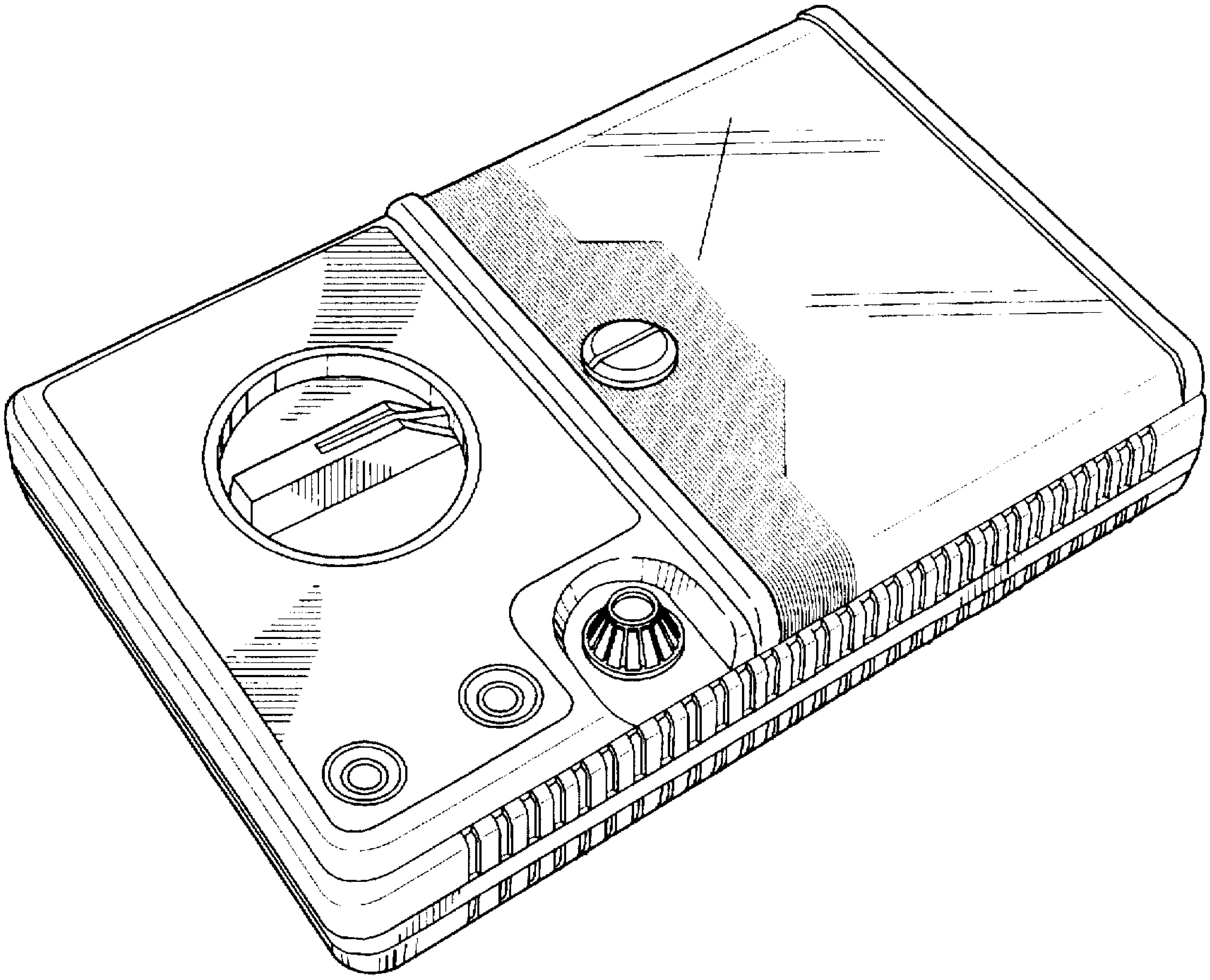

FIG. 2

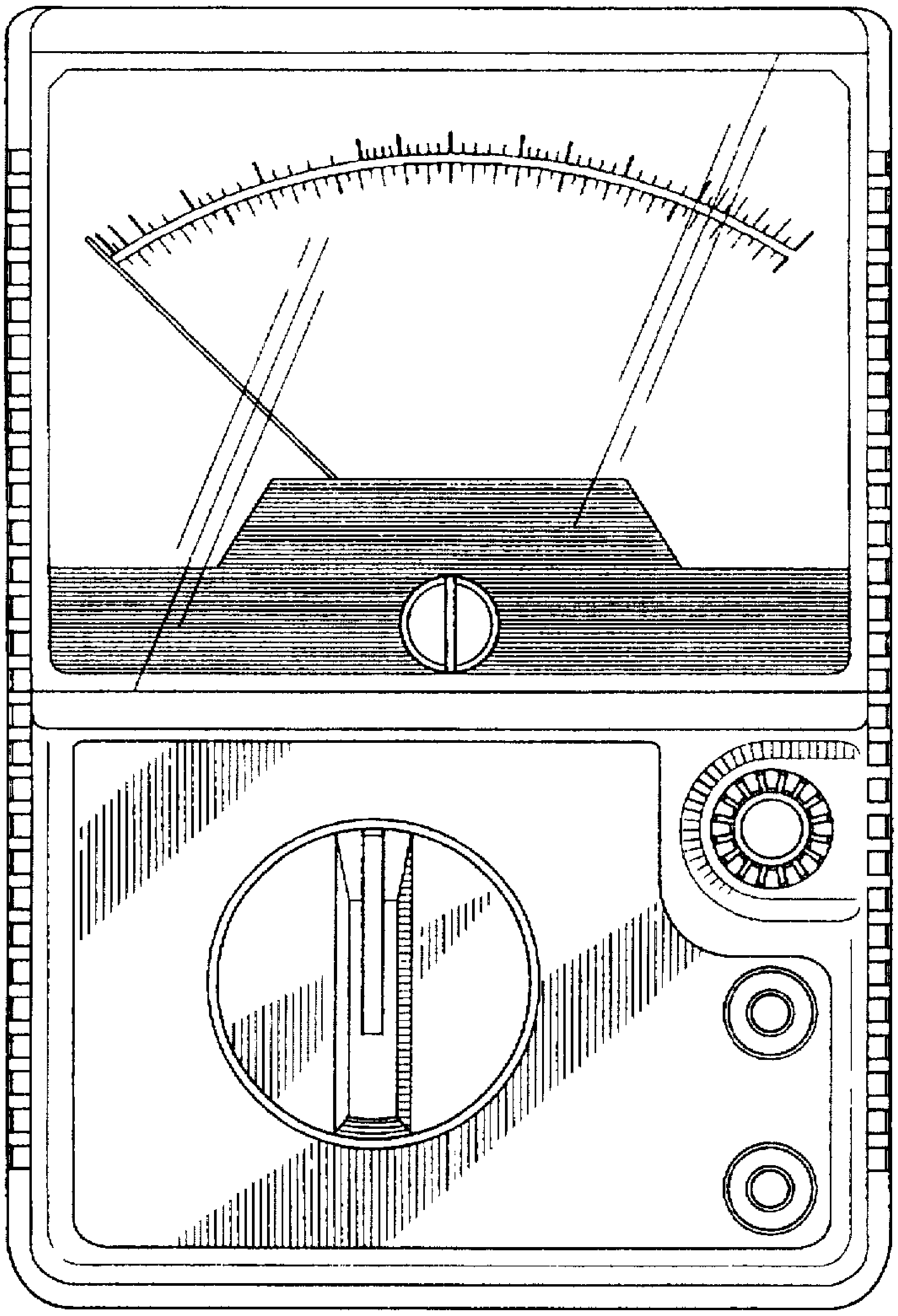

FIG. 3

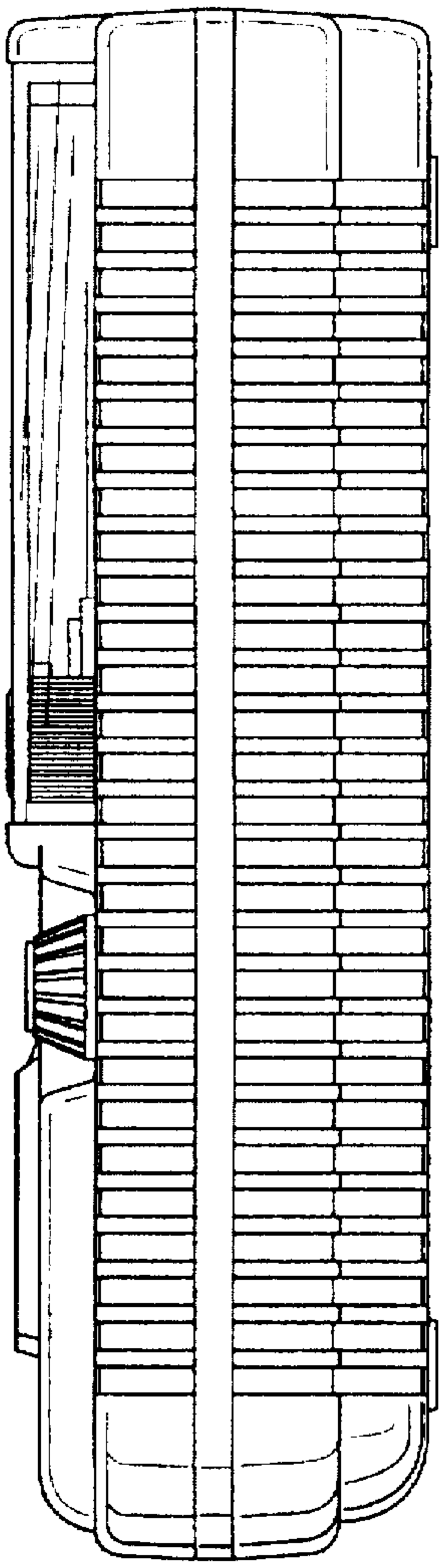

FIG. 4

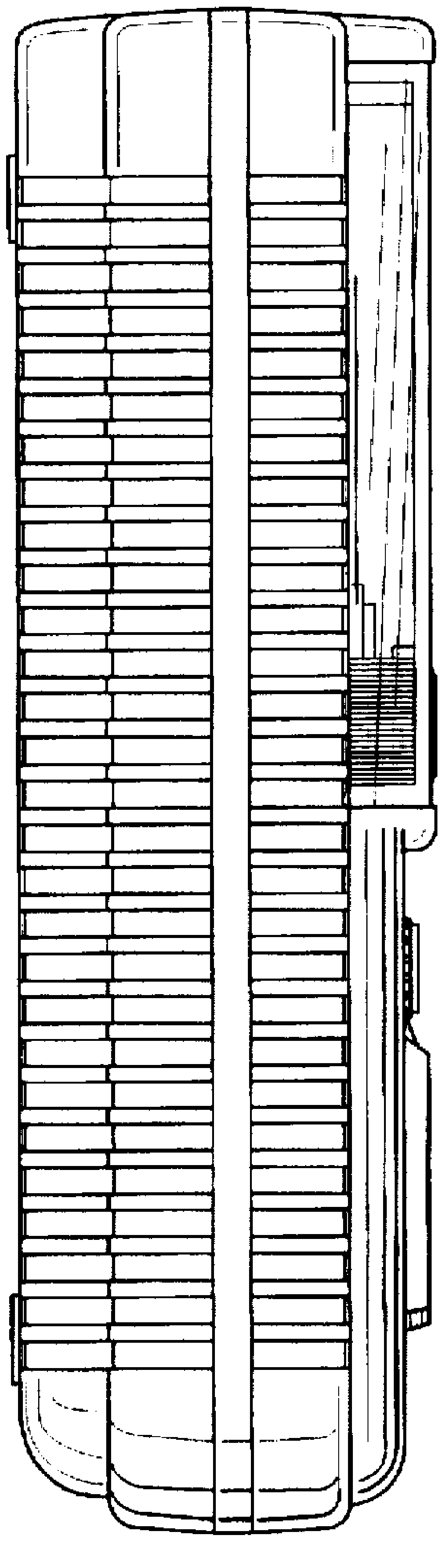

FIG. 5

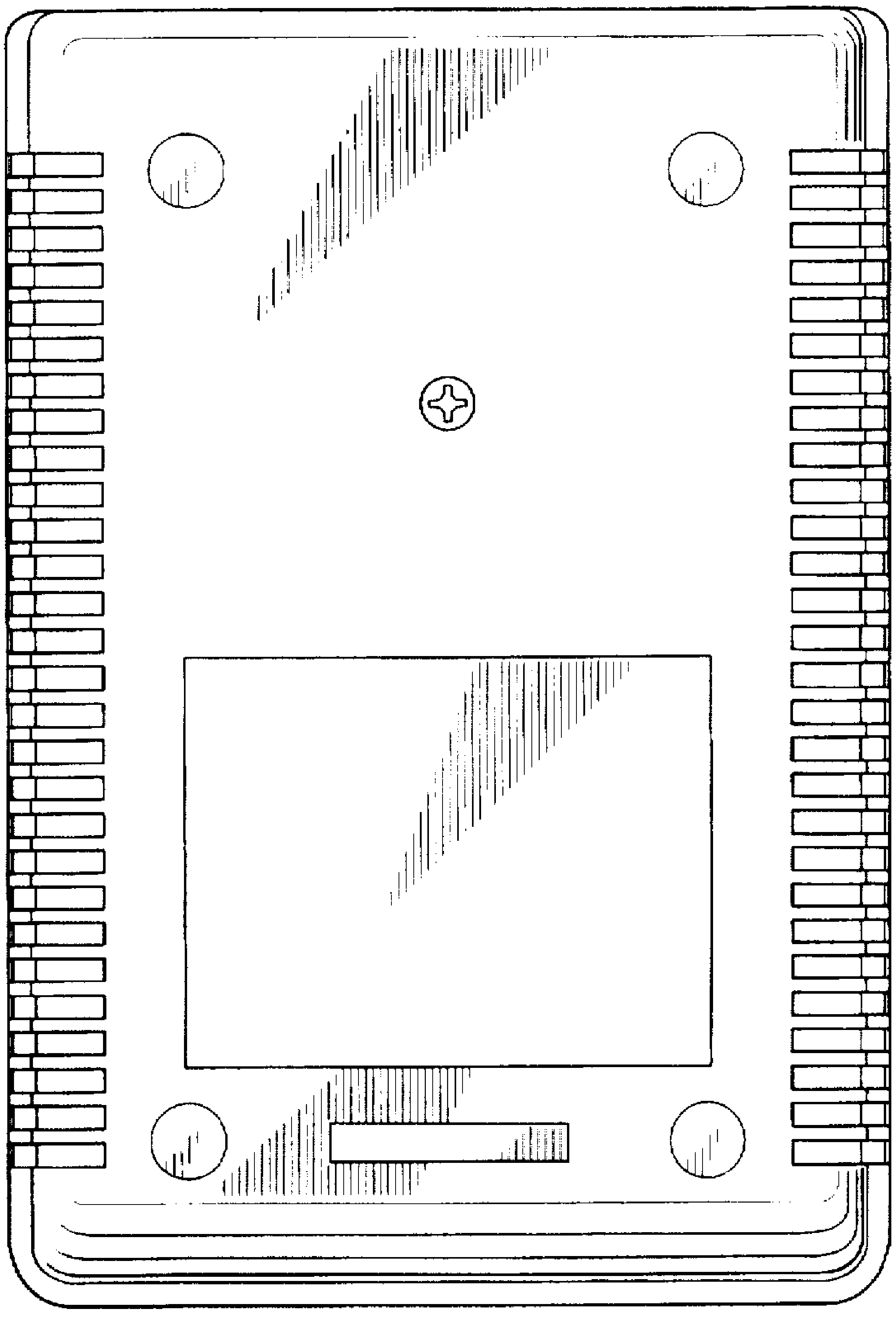

FIG. 6

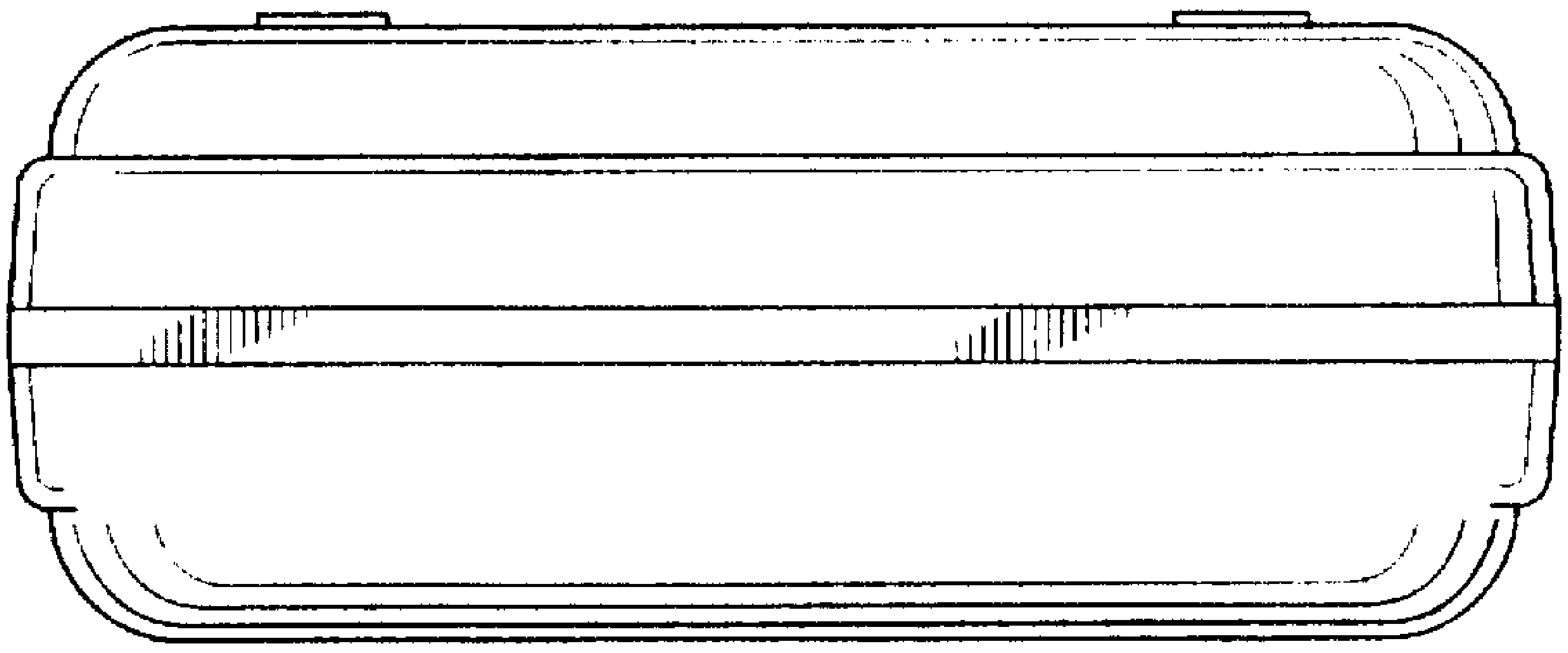

FIG. 7